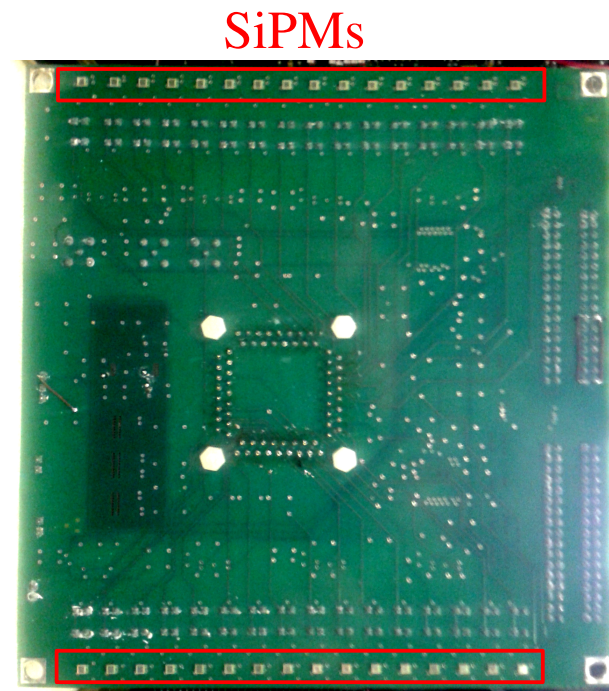
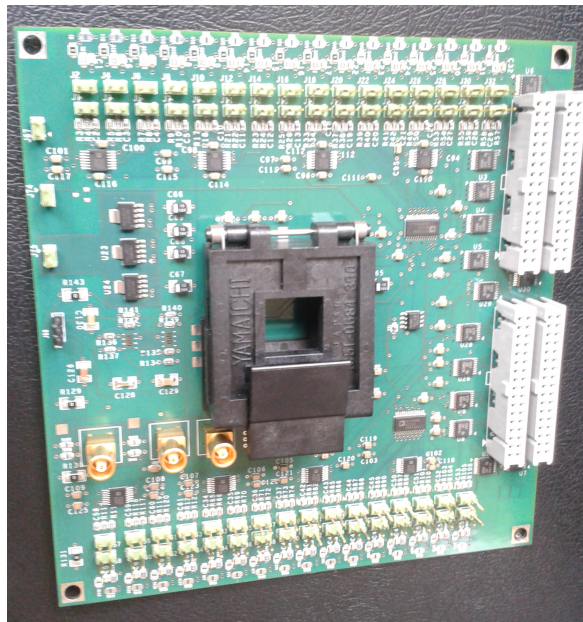


Profiler test electronics: preliminary tests of the evaluation board

Matteo Cecchetti, Giuseppe Battistoni,
Mauro Citterio, Alessandro Andreani,
Adalberto Sciubba

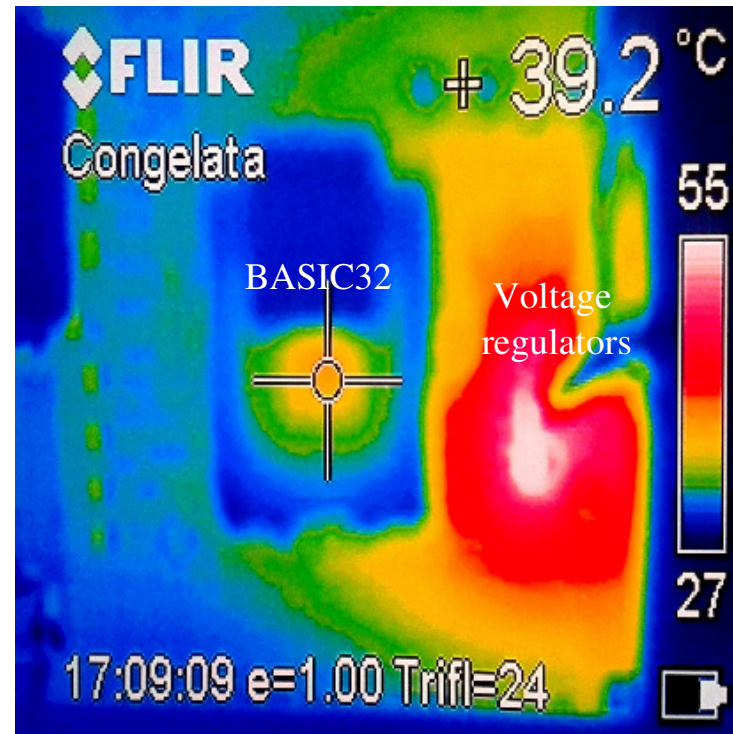
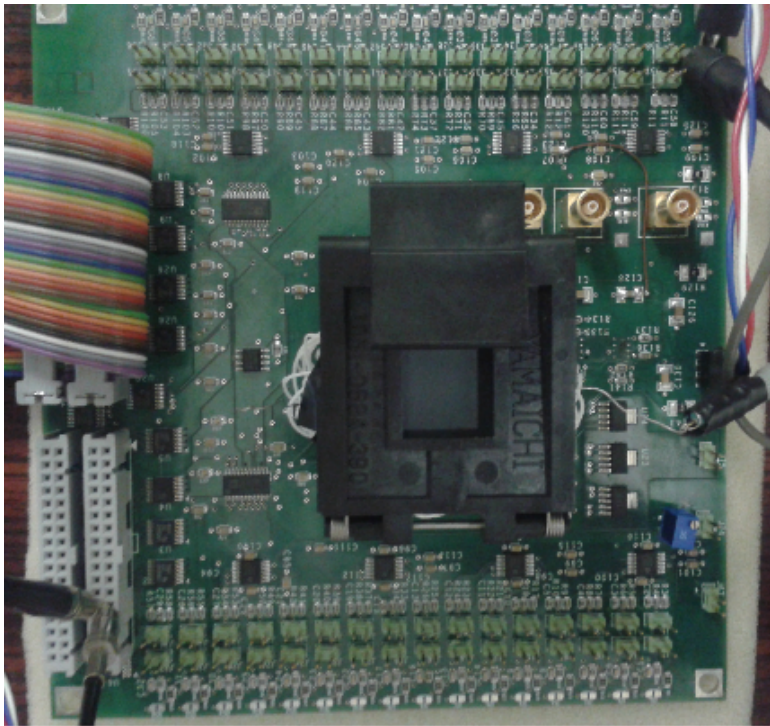
INSIDE Meeting – 18th December 2014, Roma

- ▶ The **evaluation board** has been fully assembled
- ▶ The **board testing** has begun during the first week of November
- ▶ A preliminary version of the **V1495 firmware** has been developed



Current absorption and thermal test

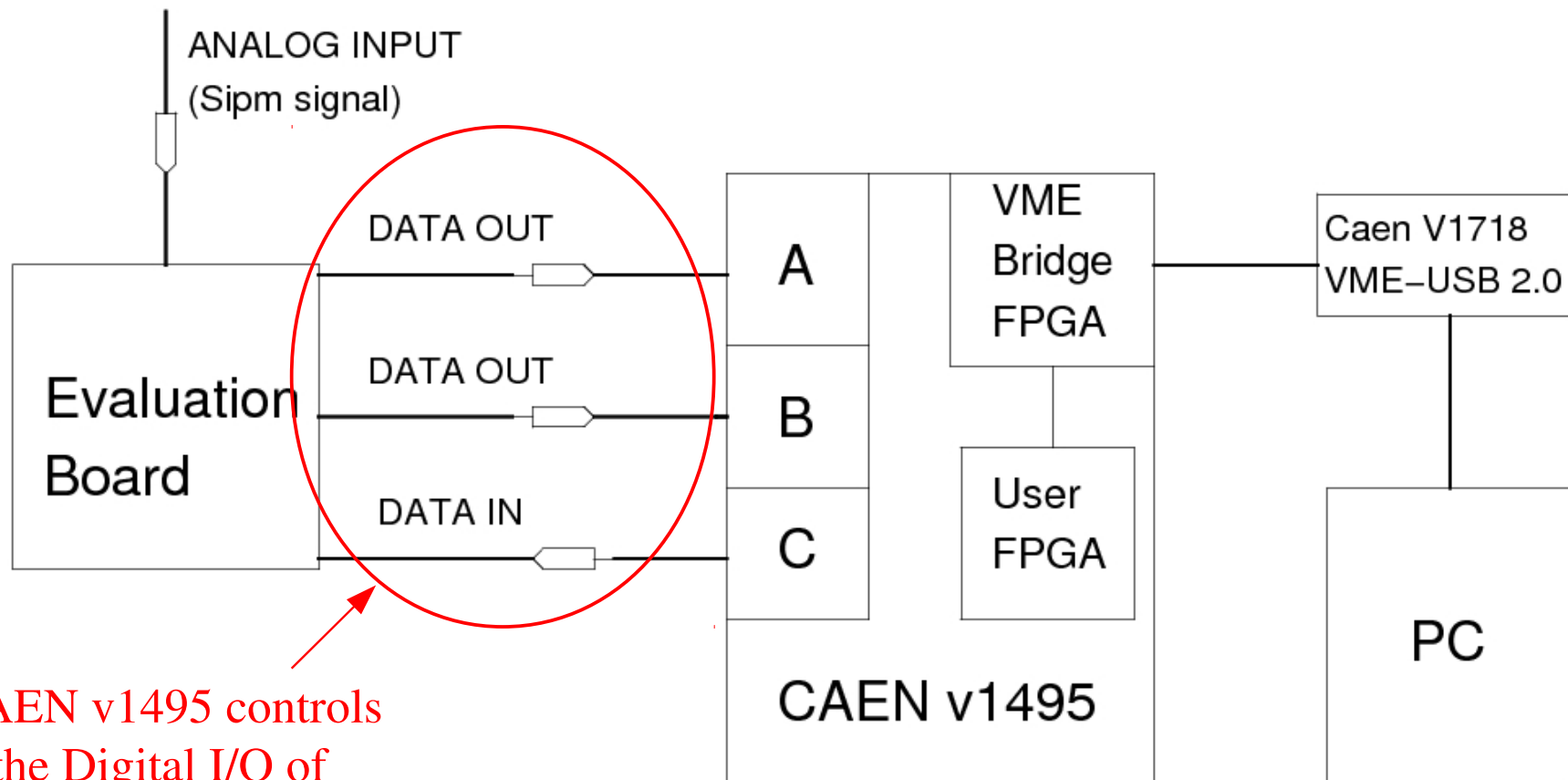
- ▶ The current absorbed by the evaluation board is approximately **200mA** when the BASIC32 is inserted, **100mA** otherwise.
- ▶ Thermal test few minutes after turning on the board



BASIC32 ~ 39°C

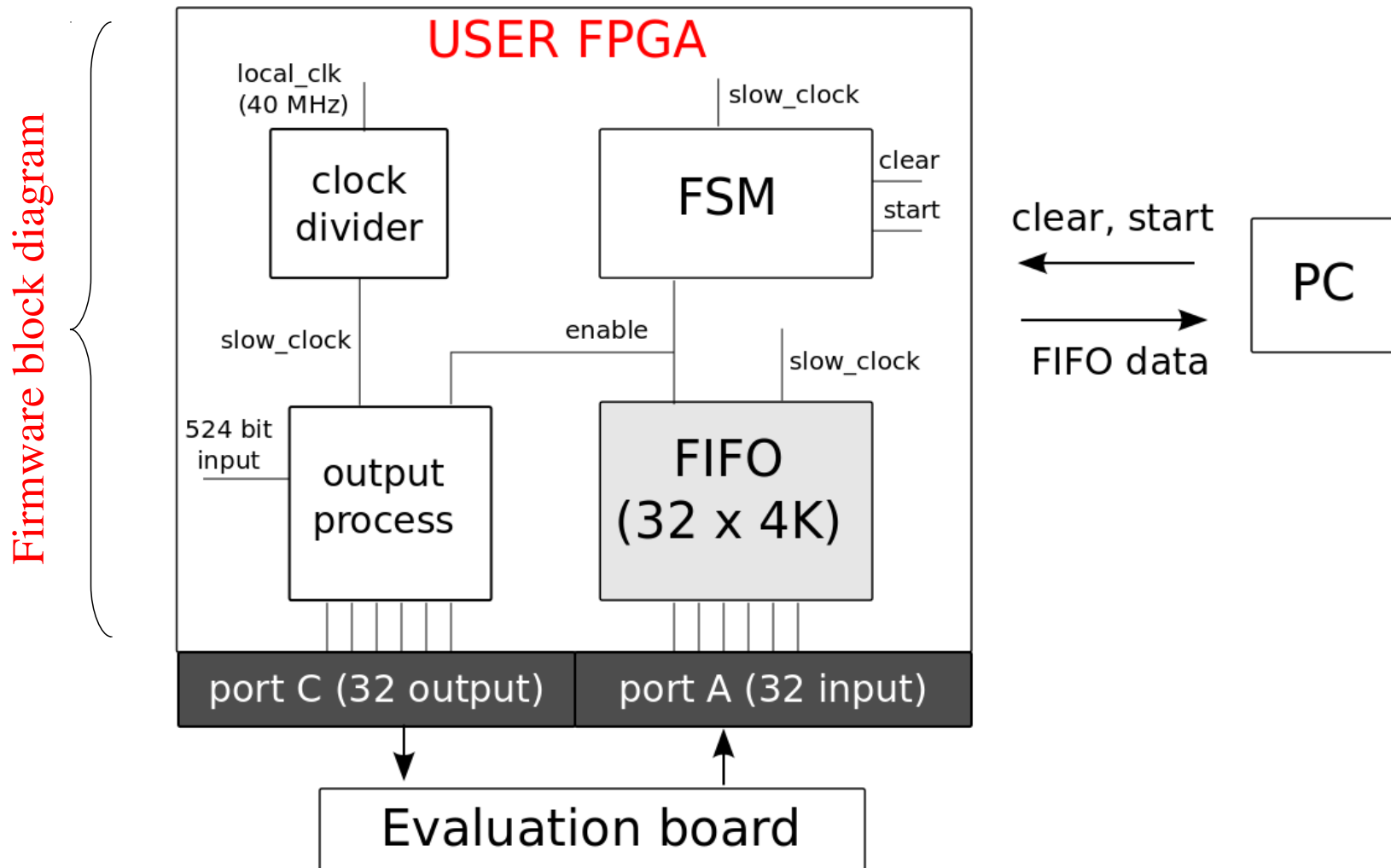
Voltage regulators ~ 55°C

- ▶ In order to test the evaluation board we need a system able to control the input signals of the board and to store the digital output.

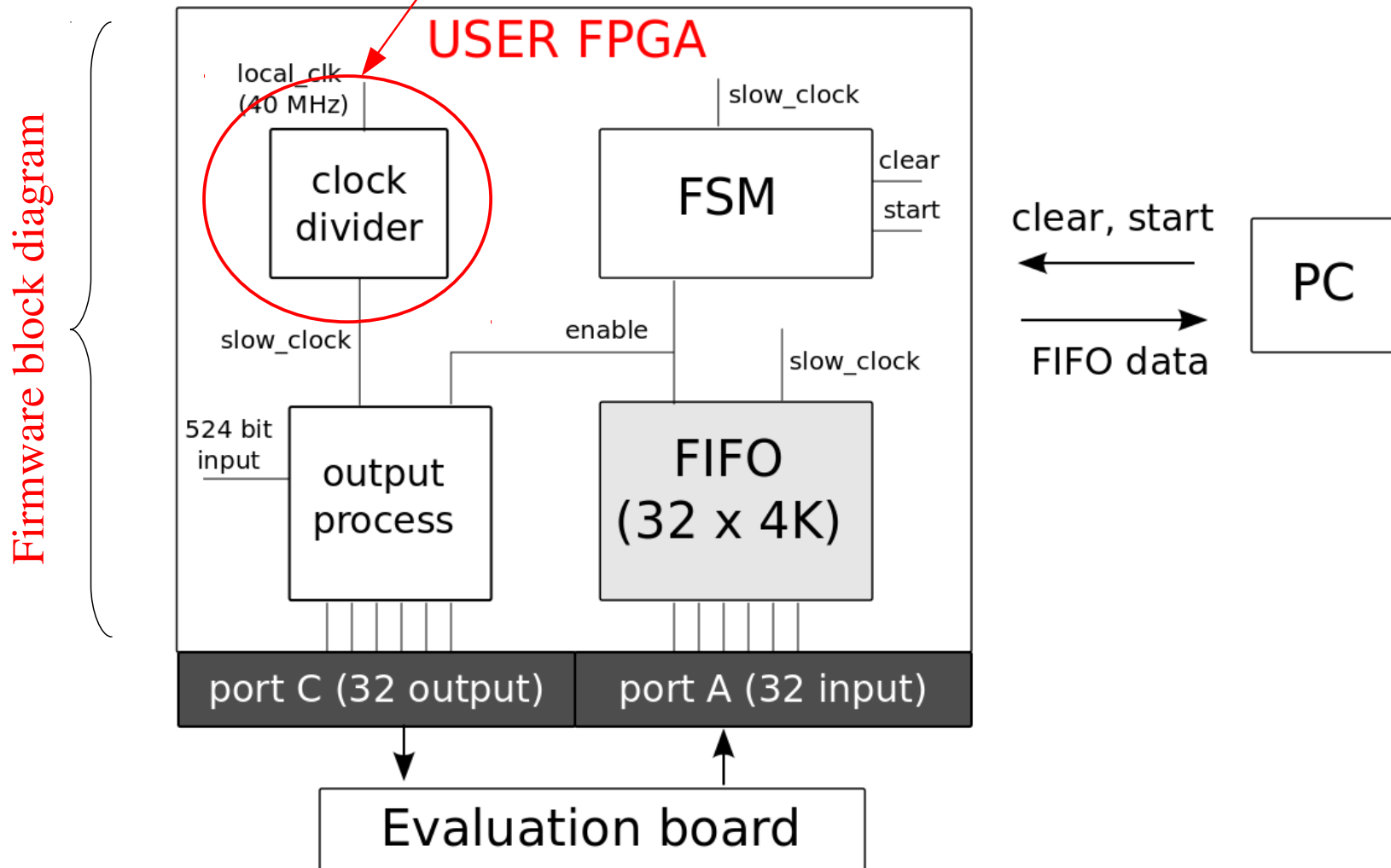


CAEN v1495 controls the Digital I/O of the evaluation board

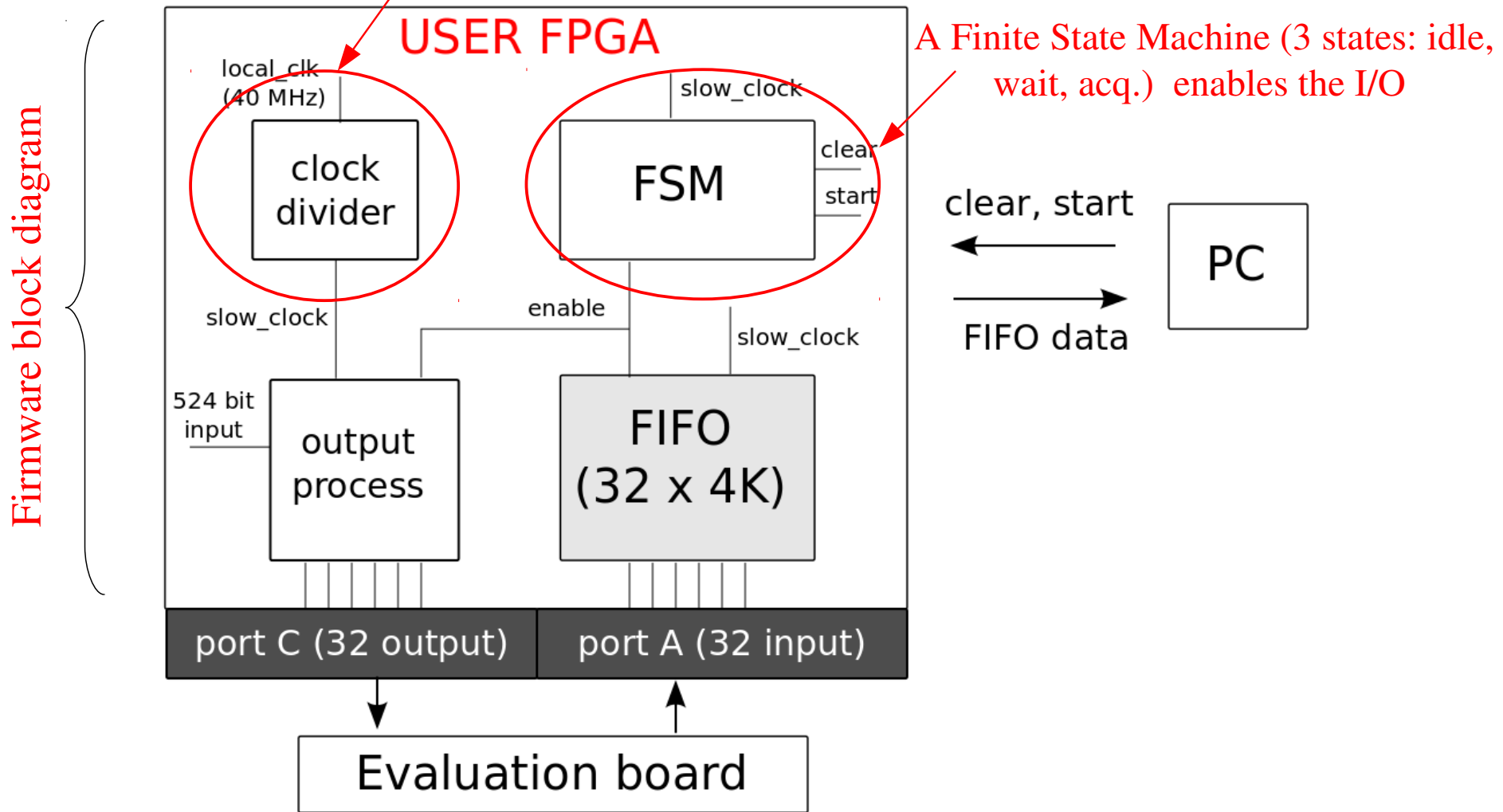
- ▶ A first version of the firmware has been developed starting from a CAEN demo.



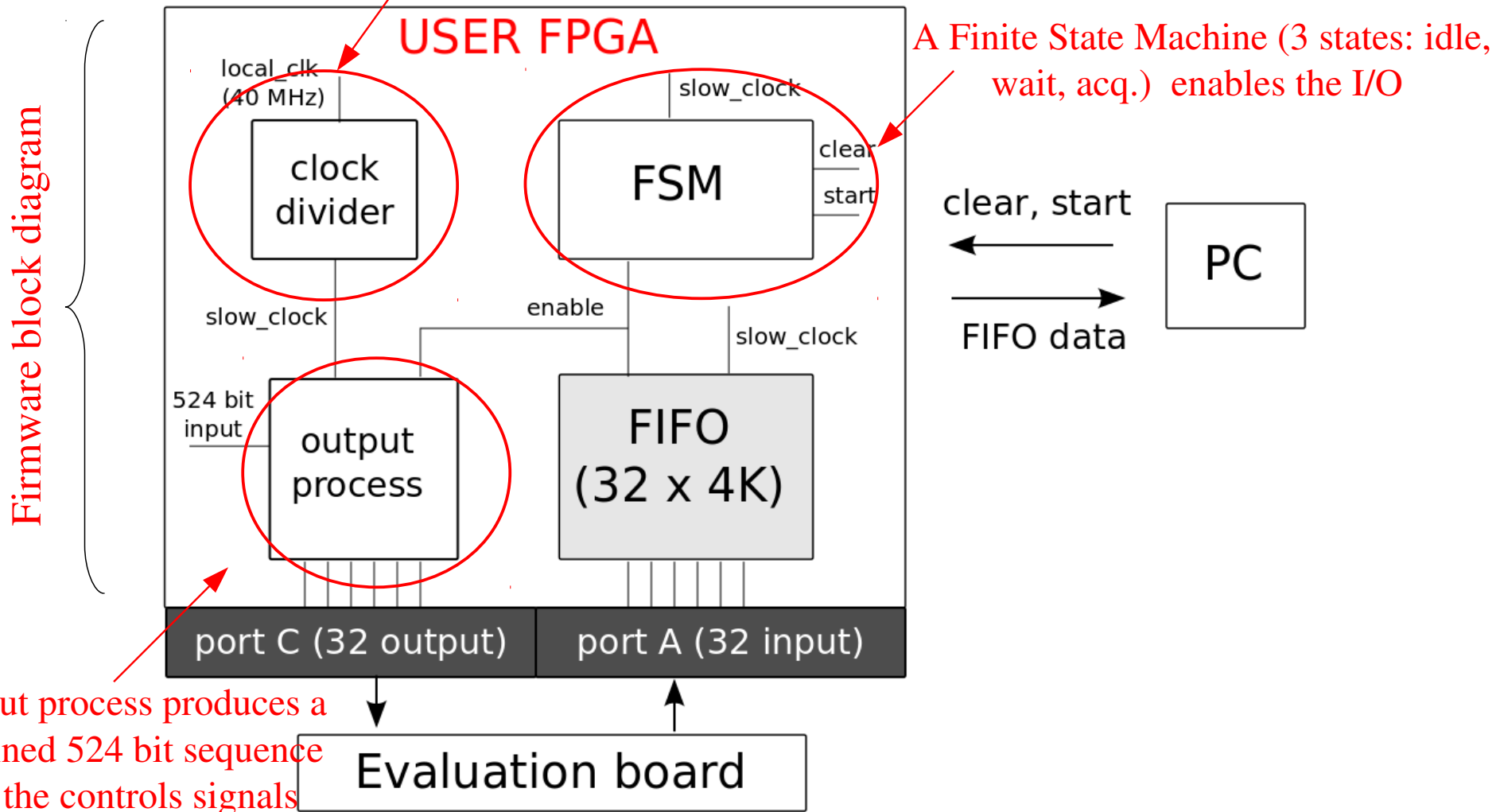
- ▶ A first version of the firmware has been developed starting from a CAEN demo. *A clock divider produces a slower clock (e.g. 1 MHz) starting from the local clock (40 MHz)*



- ▶ A first version of the firmware has been developed starting from a CAEN demo.
 A clock divider produces a slower clock (e.g. 1 MHz) starting from the local clock (40 MHz)



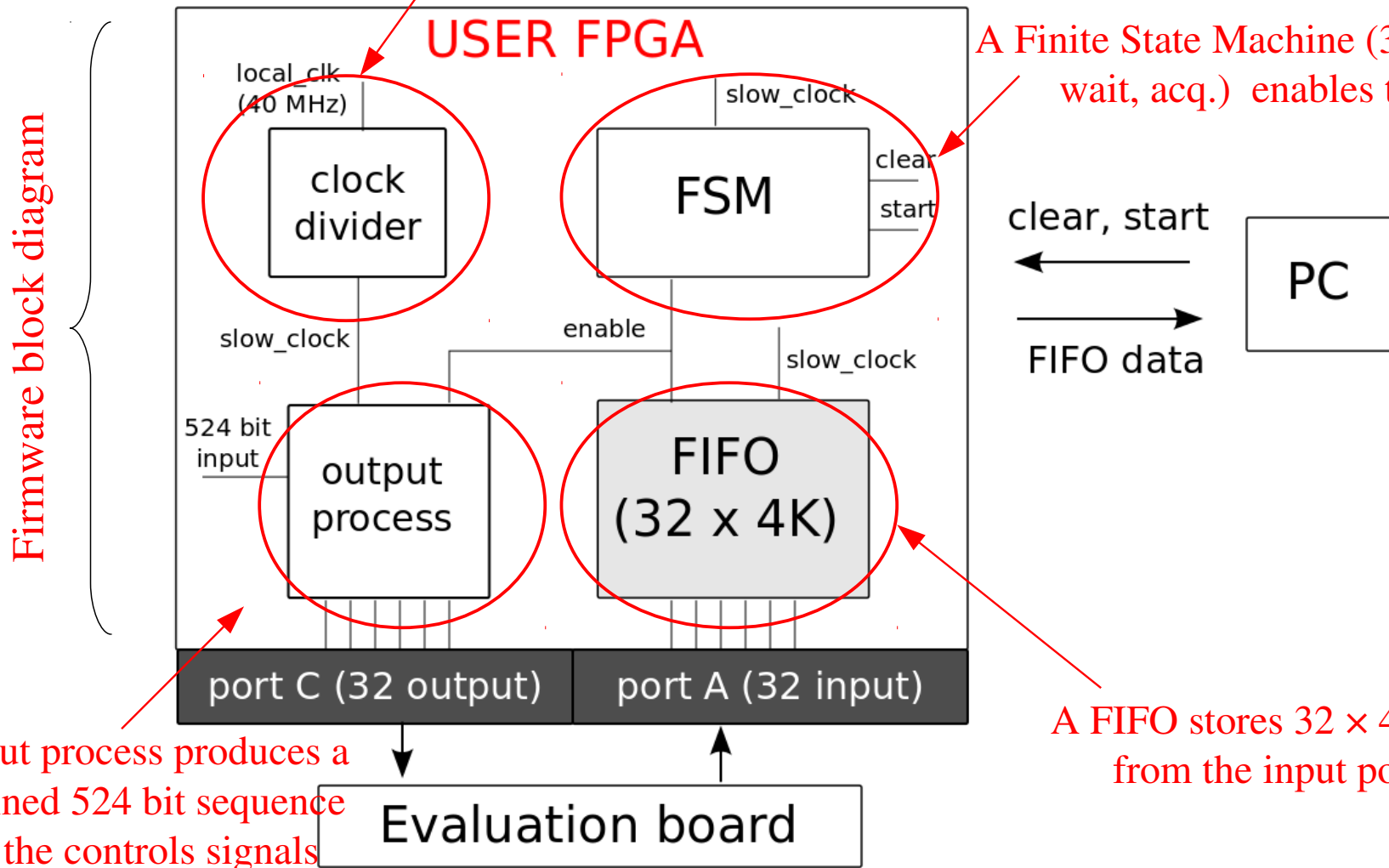
- ▶ A first version of the firmware has been developed starting from a CAEN demo.
 A clock divider produces a slower clock (e.g. 1 MHz) starting from the local clock (40 MHz)



- ▶ A first version of the firmware has been developed starting from a CAEN demo.

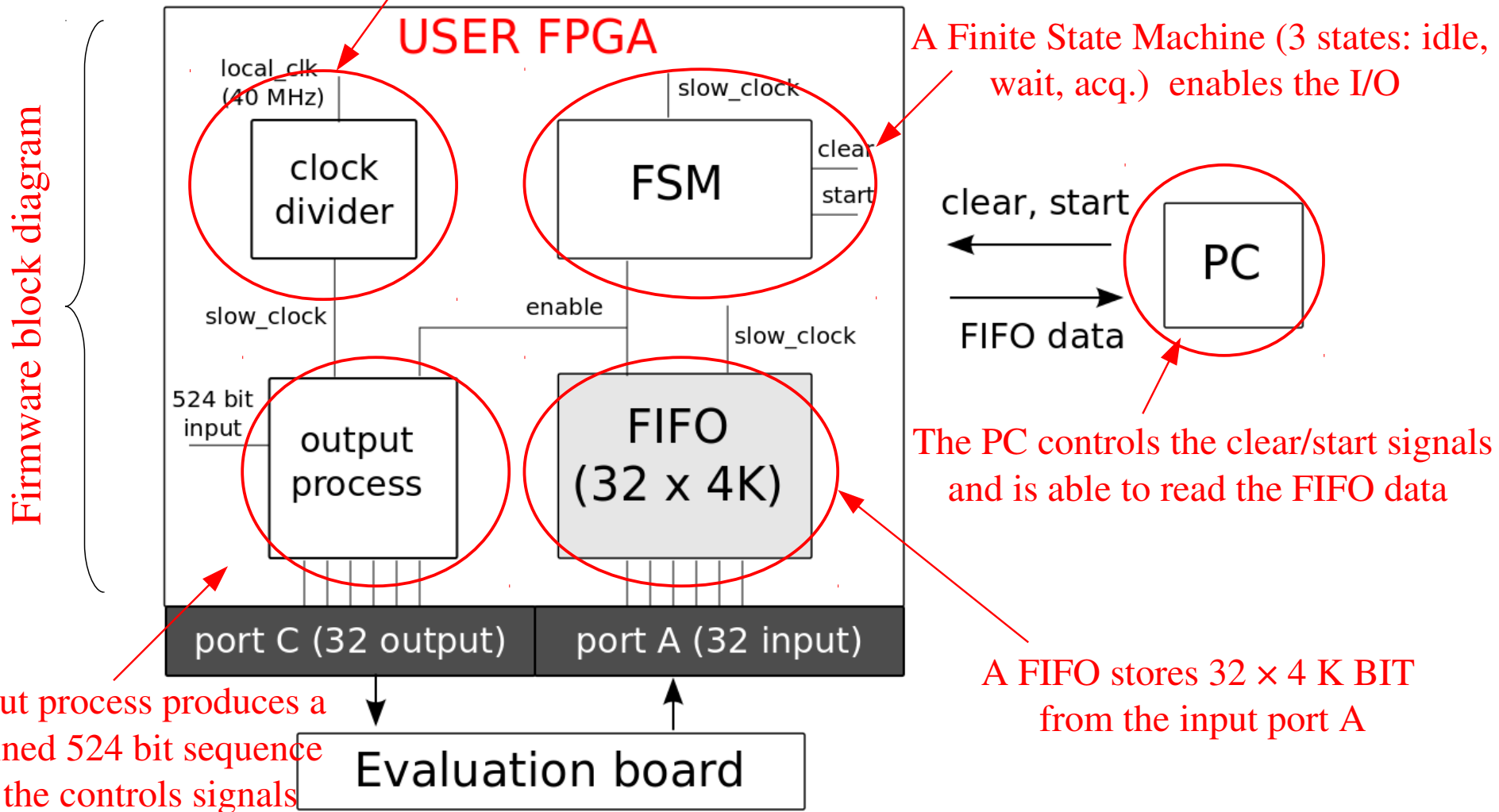
A clock divider produces a slower clock (e.g. 1 MHz) starting from the local clock (40 MHz)

A Finite State Machine (3 states: idle, wait, acq.) enables the I/O



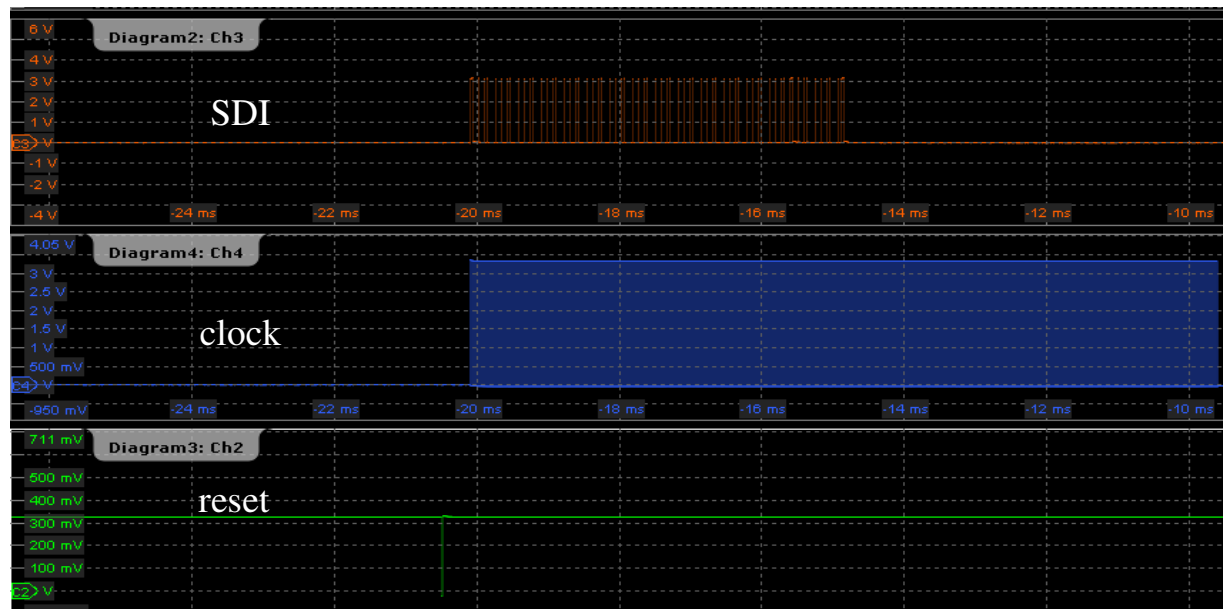
- ▶ A first version of the firmware has been developed starting from a CAEN demo.

A clock divider produces a slower clock (e.g. 1 MHz) starting from the local clock (40 MHz)



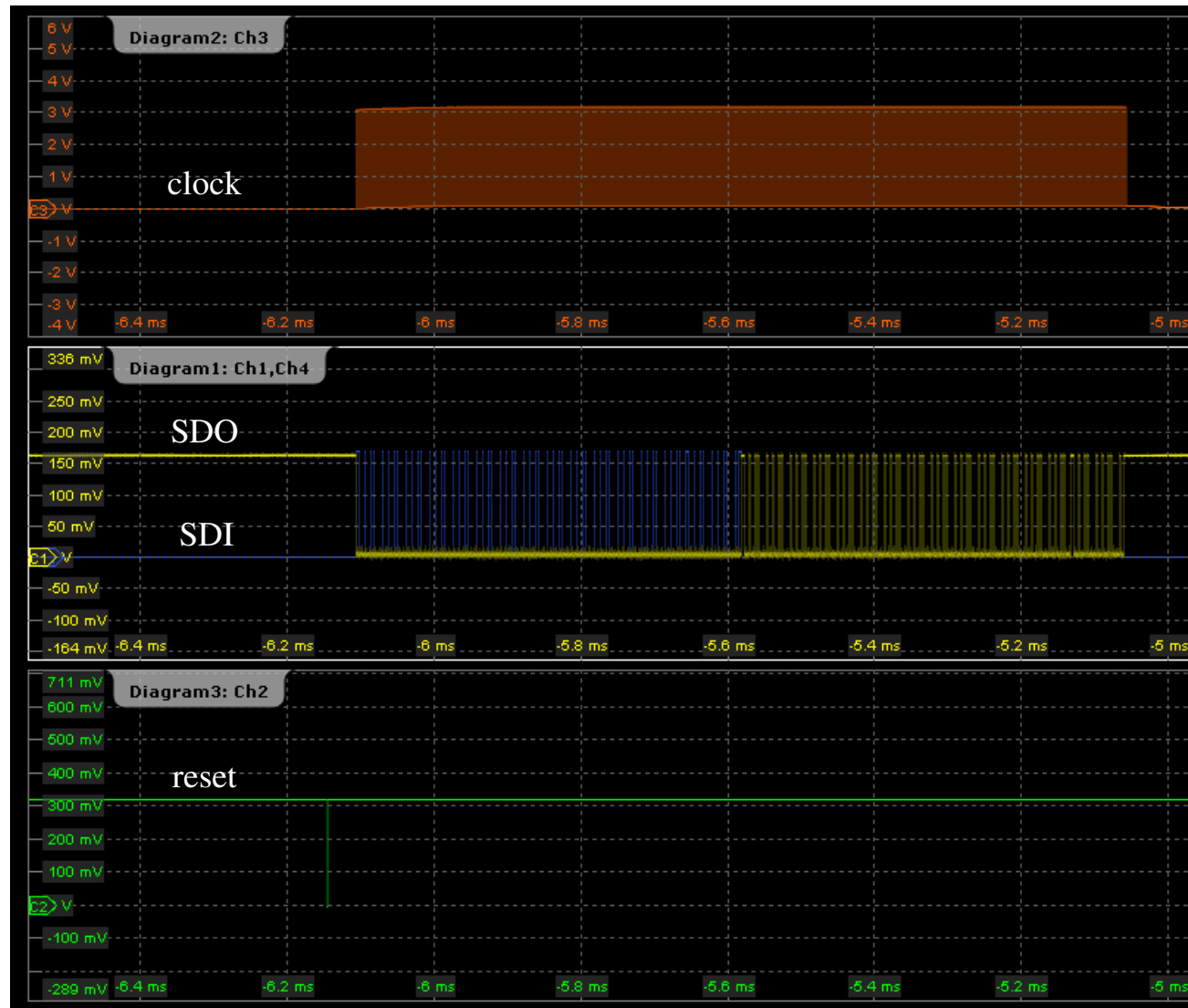
- ▶ During the first test, the serial data input (**SDI**) of the BASIC32 is driven with a 524 bits sequence and 1048 clock cycles.

FPGA output

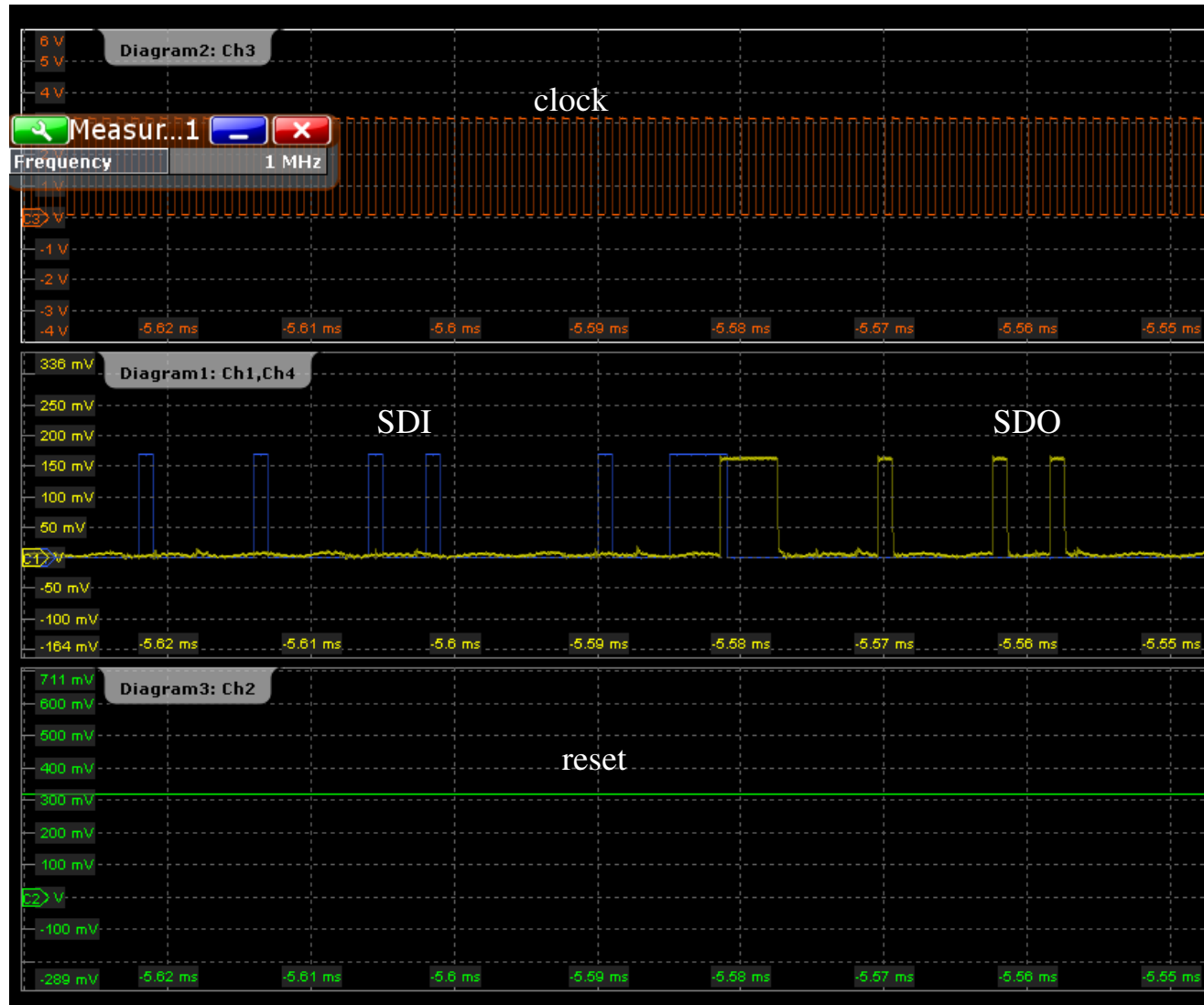


- ▶ **Expected behaviour:** in this configuration, the BASIC32 acts as a **shift register**; during the first 524 clock cycles the input sequence is stored inside the register; at the 524th clock edge the input data begin to flow through the serial data output (**SDO**)

▶ Serial I/O test at 1 MHz



Serial I/O test at 1 MHz



► Serial I/O test at 2 MHz



- ▶ Serial I/O test at 5 MHz: the system seems not working

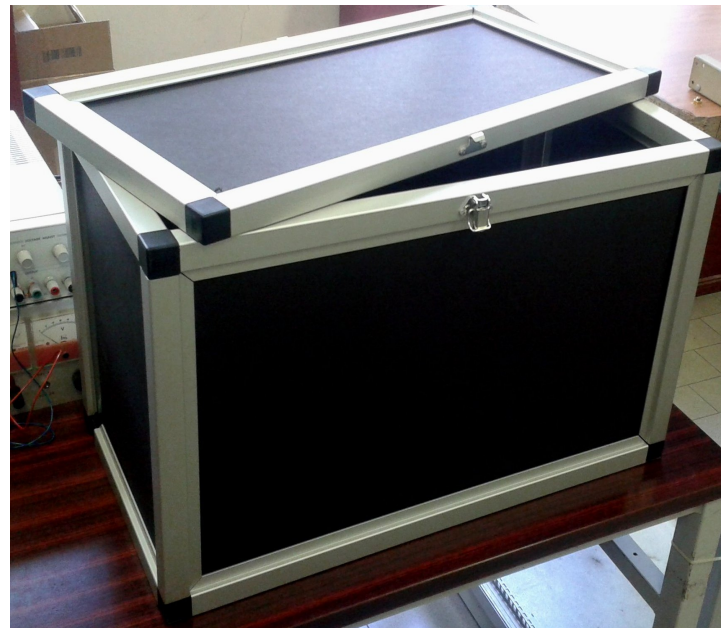


- ▶ Serial I/O test at 5 MHz: the system seems not working



Next steps

- ▶ Serial digital I/O test at high frequency ($> 2\text{MHz}$)
- ▶ Charge injection test on the BASIC32 analog input channels
- ▶ SiPM input test within the Light Tight Enclosure (Newport LTE-12)



Thanks for your attention!